# MSKSEMI 美森科













ESD

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TSS

MOV

GDT

PIFD

BAS40-XXLT1G(MS)

**Product specification** 





#### **SCHOTTKY BARRIERDIODE**

#### **FEATURES**

- Low Forward Voltage
- Fast Switching

#### **Reference News**

PACKAGE OUTLINE	BAS40LT1G(MS)	BAS40-06LT1G(MS)	BAS40-05LT1G(MS)	BAS40-04LT1G(MS)
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1 2	43	46	45	44
SOT-23	MARKING:43	MARKING:46	MARKING:45	MARKING:44

# Maximum Ratings @Ta=25℃

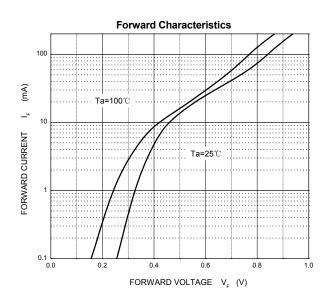
Parameter	Symbol	Limit	Unit
Peak repetitive peak reverse voltage	V <sub>RRM</sub>		
Working peak reverse voltage	V <sub>RWM</sub>	40	V
DC blocking voltage	$V_R$		
Forward continuous current	I <sub>FM</sub>	200	mA
Power dissipation	P <sub>D</sub>	200	mW
Thermal resistance junction to ambient	Reja	500	°C/W
Junction temperature	TJ	125	${\mathbb C}$
Storage temperature range	T <sub>STG</sub>	-55~+150	°C

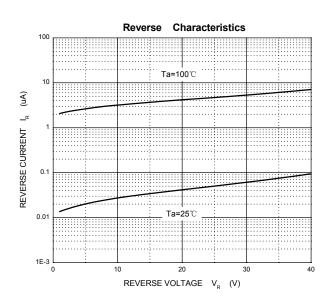
# **ELECTRICAL CHARACTERISTICS (Ta=25℃ unless otherwise specified)**

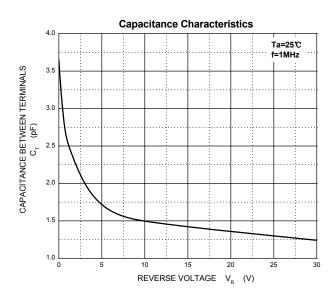
Parameter	Symbol	Test conditions	Min	Max	Unit
Reverse breakdown voltage	V <sub>(BR)</sub>	l <sub>R</sub> =10µA	40		V
Reverse voltage leakage current	<b>I</b> R	V <sub>R</sub> =30V		200	nA
Forward voltage	V <sub>F</sub>	l=1mA l=40mA		380 1000	mV
Diode capacitance	C <sub>D</sub>	V <sub>R</sub> =0,f=1MHz		5	pF
Reverse recovery time	t rr	$I_{rr}$ =1mA, $I_{R}$ = $I_{F}$ =10mA $R_{L}$ =100 $\Omega$		5	ns

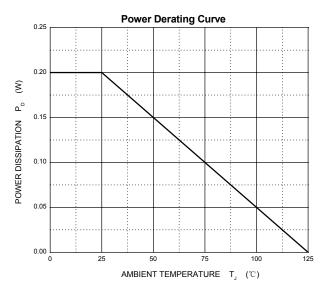


# **Typical Characteristics**



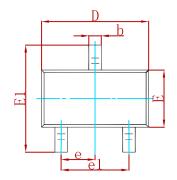


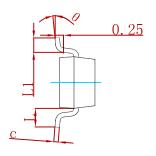


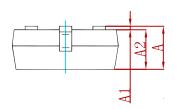




## PACKAGE MECHANICAL DATA

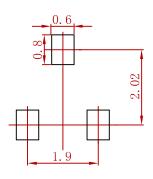






Symbol	Dimensions In Millimeters		Dimensions In Inches	
Зунион	Min	Max	Min	Max
Α	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
С	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
е	0.950 TYP		0.037 TYP	
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022	REF
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

# **Suggested Pad Layout**



- 1.Controlling dimension:in millimeters. 2.General tolerance:± 0.05mm.
- 3. The pad layout is for reference purposes only.

### **REELSPECIFICATION**

P/N	PKG	QTY
BAS40-XXLT1G(MS)	SOT-23	3000



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